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Understanding Embedded - Microprocessors

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of Embedded - Microprocessors

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details	
Product Status	Obsolete
Core Processor	PowerPC G4
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	1GHz
Co-Processors/DSP	Multimedia; SIMD
RAM Controllers	-
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	-
SATA	-
USB	-
Voltage - I/O	1.5V, 1.8V, 2.5V
Operating Temperature	-40°C ~ 105°C (TA)
Security Features	-
Package / Case	483-BCBGA, FCCBGA
Supplier Device Package	483-FCCBGA (29x29)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mc7457trx1000nc

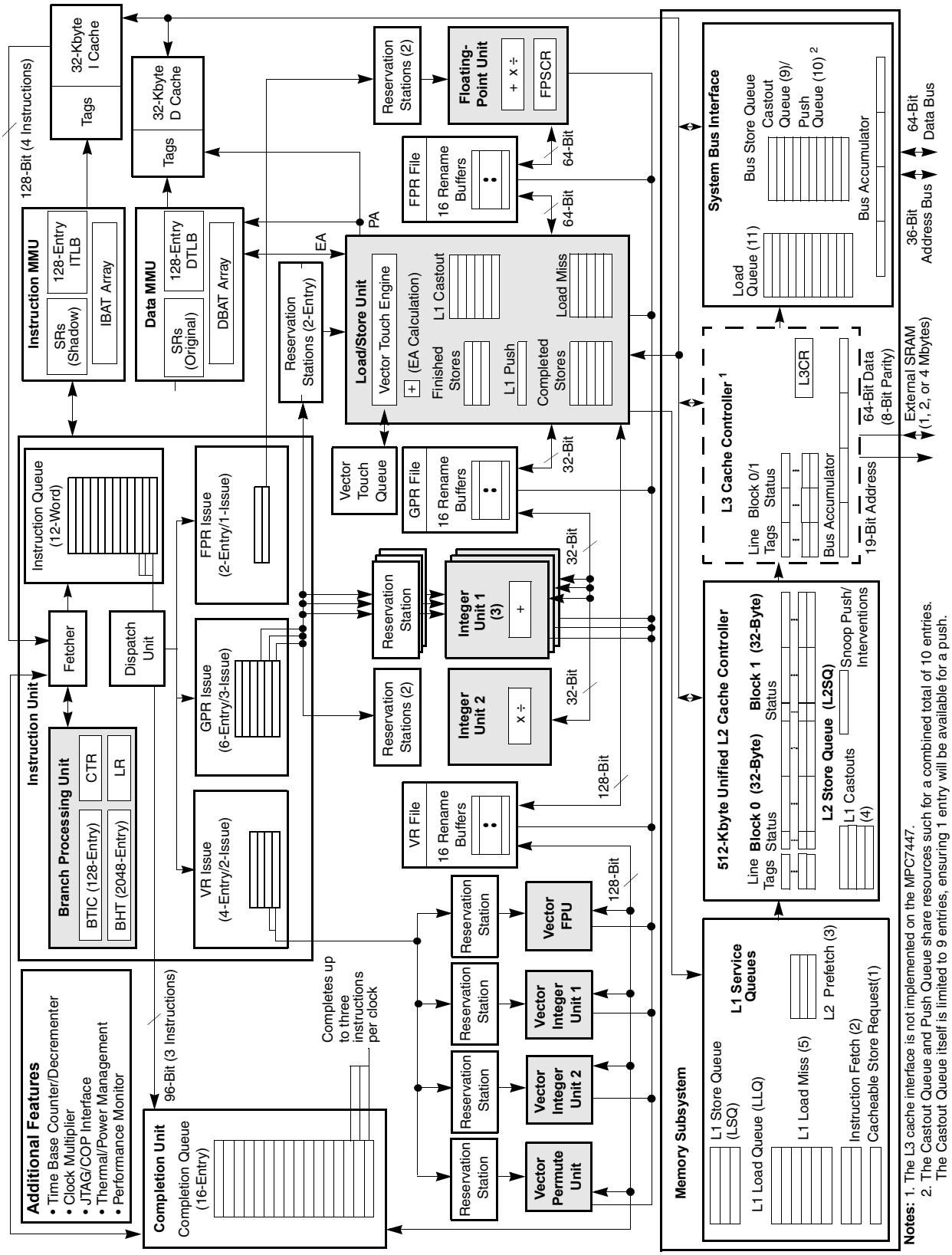


Figure 1. MPC7457 Block Diagram

  - Space must be available in the CQ for an instruction to dispatch (this includes instructions that are assigned a space in the CQ but not in an issue queue)
- Rename buffers
  - 16 GPR rename buffers
  - 16 FPR rename buffers
  - 16 VR rename buffers
- Dispatch unit
  - Decode/dispatch stage fully decodes each instruction
- Completion unit
  - The completion unit retires an instruction from the 16-entry completion queue (CQ) when all instructions ahead of it have been completed, the instruction has finished execution, and no exceptions are pending.
  - Guarantees sequential programming model (precise exception model)
  - Monitors all dispatched instructions and retires them in order
  - Tracks unresolved branches and flushes instructions after a mispredicted branch
  - Retires as many as three instructions per clock cycle
- Separate on-chip L1 instruction and data caches (Harvard architecture)
  - 32-Kbyte, eight-way set associative instruction and data caches
  - Pseudo least recently used (PLRU) replacement algorithm
  - 32-byte (eight-word) L1 cache block
  - Physically indexed/physical tags
  - Cache write-back or write-through operation programmable on a per-page or per-block basis
  - Instruction cache can provide four instructions per clock cycle; data cache can provide four words per clock cycle
  - Caches can be disabled in software.
  - Caches can be locked in software.
  - MESI data cache coherency maintained in hardware
  - Separate copy of data cache tags for efficient snooping
  - L1 cache supports parity generation and checking
  - No snooping of instruction cache except for **icbi** instruction
  - Data cache supports AltiVec LRU and transient instructions
  - Critical double- and/or quad-word forwarding is performed as needed. Critical quad-word forwarding is used for AltiVec loads and instruction fetches. Other accesses use critical double-word forwarding.
- Level 2 (L2) cache interface
  - On-chip, 512-Kbyte, eight-way set associative unified instruction and data cache
  - Fully pipelined to provide 32 bytes per clock cycle to the L1 caches
  - A total nine-cycle load latency for an L1 data cache miss that hits in L2

  - Store merging for multiple store misses to the same line. Only coherency action taken (address-only) for store misses merged to all 32 bytes of a cache block (no data tenure needed).
  - Three-entry finished store queue and five-entry completed store queue between the LSU and the L1 data cache
  - Separate additional queues for efficient buffering of outbound data (such as castouts and write-through stores) from the L1 data cache and L2 cache
- Multiprocessing support features include the following:
  - Hardware-enforced, MESI cache coherency protocols for data cache
  - Load/store with reservation instruction pair for atomic memory references, semaphores, and other multiprocessor operations
- Power and thermal management
  - 1.3-V processor core
  - The following three power-saving modes are available to the system:
    - Nap—Instruction fetching is halted. Only those clocks for the time base, decrementer, and JTAG logic remain running. The part goes into the doze state to snoop memory operations on the bus and back to nap using a $\overline{\text{QREQ}}$/$\overline{\text{QACK}}$ processor-system handshake protocol.
    - Sleep—Power consumption is further reduced by disabling bus snooping, leaving only the PLL in a locked and running state. All internal functional units are disabled.
    - Deep sleep—When the part is in the sleep state, the system can disable the PLL. The system can then disable the SYSCLK source for greater system power savings. Power-on reset procedures for restarting and relocking the PLL must be followed on exiting the deep sleep state.
  - Thermal management facility provides software-controllable thermal management. Thermal management is performed through the use of three supervisor-level registers and an MPC7457-specific thermal management exception.
  - Instruction cache throttling provides control of instruction fetching to limit power consumption
- Performance monitor can be used to help debug system designs and improve software efficiency
- In-system testability and debugging features through JTAG boundary-scan capability
- Testability
  - LSSD scan design
  - IEEE 1149.1 JTAG interface
  - Array built-in self test (ABIST)—factory test only
- Reliability and serviceability
  - Parity checking on system bus and L3 cache bus
  - Parity checking on the L2 and L3 cache tag arrays

Table 5. Package Thermal Characteristics [1] (continued)

Characteristic	Symbol	Value		Unit	Notes
		MPC7447	MPC7457		
Coefficient of thermal expansion		6.8	6.8	ppm/°C	

Notes:
1. Refer to Section 9.8, "Thermal Management Information," for more details about thermal management.
2. Junction temperature is a function of on-chip power dissipation, package thermal resistance, mounting site (board) temperature, ambient temperature, airflow, power dissipation of other components on the board, and board thermal resistance.
3. Per SEMI G38-87 and JEDEC JESD51-2 with the single-layer board horizontal.
4. Per JEDEC JESD51-6 with the board horizontal.
5. Thermal resistance between the die and the printed-circuit board per JEDEC JESD51-8. Board temperature is measured on the top surface of the board near the package.
6. Thermal resistance between the die and the case top surface as measured by the cold plate method (MIL SPEC-883 Method 1012.1) with the calculated case temperature. The actual value of $R_{\theta JC}$ for the part is less than 0.1°C/W.

Table 6 provides the DC electrical characteristics for the MPC7457.

Table 6. DC Electrical Specifications

At recommended operating conditions. See Table 4.

Characteristic	Nominal Bus Voltage [1]	Symbol	Min	Max	Unit	Notes
Input high voltage (all inputs including SYSCLK)	1.5	V_{IH}	$GV_{DD} \times 0.65$	$GV_{DD} + 0.3$	V	2
	1.8		$OV_{DD}/GV_{DD} \times 0.65$	$OV_{DD}/GV_{DD} + 0.3$	V	
	2.5		1.7	$OV_{DD}/GV_{DD} + 0.3$	V	
Input low voltage (all inputs including SYSCLK)	1.5	V_{IL}	–0.3	$GV_{DD} \times 0.35$	V	2, 6
	1.8		–0.3	$OV_{DD}/GV_{DD} \times 0.35$	V	
	2.5		–0.3	0.7	V	
Input leakage current, $V_{in} = GV_{DD}/OV_{DD}$	—	I_{in}	—	30	µA	2, 3
High-impedance (off-state) leakage current, $V_{in} = GV_{DD}/OV_{DD}$	—	I_{TSI}	—	30	µA	2, 3, 4
Output high voltage, $I_{OH} = –5$ mA	1.5	V_{OH}	$OV_{DD}/GV_{DD} – 0.45$	—	V	6
	1.8		$OV_{DD}/GV_{DD} – 0.45$	—	V	
	2.5		1.8	—	V	
Output low voltage, $I_{OL} = 5$ mA	1.5	V_{OL}	—	0.45	V	6
	1.8		—	0.45	V	
	2.5		—	0.6	V	

window at the internal receiving latches. This delayed clock is used to capture the data into these latches which comprise the receive FIFO. This clock is asynchronous to all other processor clocks. This latched data is subsequently read out of the FIFO synchronously to the processor clock. The time between writing and reading the data is set by the using the sample point settings defined in the L3CR register.

Table 13 provides the L3 bus interface AC timing specifications for the configuration as shown in Figure 9, assuming the timing relationships shown in Figure 10 and the loading shown in Figure 8.

Table 13. L3 Bus Interface AC Timing Specifications for MSUG2

At recommended operating conditions. See Table 4.

Parameter	Symbol	Device Revision (L3 I/O Voltage) [9]				Unit	Notes
		Rev 1.1. (All I/O Modes) Rev 1.2 (1.5-V I/O Mode)		Rev 1.2 (1.8-, 2.5-V I/O Modes)			
		Min	Max	Min	Max		
L3_CLK rise and fall time	t_{L3CR}, t_{L3CF}	—	0.75	—	0.75	ns	1
Setup times: Data and parity	t_{L3DVEH}, t_{L3DVEL}	$(-t_{L3CLK}/4) + 0.90$	—	$(-t_{L3CLK}/4) + 0.70$	—	ns	2, 3, 4
Input hold times: Data and parity	t_{L3DXEH}, t_{L3DXEL}	$(t_{L3CLK}/4) + 0.85$	—	$(t_{L3CLK}/4) + 0.70$	—	ns	2, 4
Valid times: Data and parity	t_{L3CHDV}, t_{L3CLDV}	—	$(-t_{L3CLK}/4) + 0.60$	—	$(-t_{L3CLK}/4) + 0.50$	ns	5, 6, 7, 8
Valid times: All other outputs	t_{L3CHOV}	—	$(t_{L3CLK}/4) + 0.65$	—	$(t_{L3CLK}/4) + 0.65$	ns	5, 7, 8
Output hold times: Data and parity	t_{L3CHDX}, t_{L3CLDX},	$(t_{L3CLK}/4) - 0.60$	—	$(t_{L3CLK}/4) - 0.50$	—	ns	5, 6, 7, 8
Output hold times: All other outputs	t_{L3CHOX}	$(t_{L3CLK}/4) - 0.50$	—	$(t_{L3CLK}/4) - 0.50$	—	ns	5, 7, 8
L3_CLK to high impedance: Data and parity	t_{L3CLDZ}	—	$(-t_{L3CLK}/4) + 0.60$	—	$(-t_{L3CLK}/4) + 0.60$	ns	

Table 13. L3 Bus Interface AC Timing Specifications for MSUG2 (continued)

At recommended operating conditions. See Table 4.

Parameter	Symbol	Device Revision (L3 I/O Voltage) [9]				Unit	Notes
		Rev 1.1. (All I/O Modes) Rev 1.2 (1.5-V I/O Mode)		Rev 1.2 (1.8-, 2.5-V I/O Modes)			
		Min	Max	Min	Max		
L3_CLK to high impedance: All other outputs	t_{L3CHOZ}	—	(t_{L3CLK}/4) + 0.65	—	(t_{L3CLK}/4) + 0.65	ns	

Notes:

1. Rise and fall times for the L3_CLK output are measured from 20% to 80% of GV_{DD}.
2. For DDR, all input specifications are measured from the midpoint of the signal in question to the midpoint voltage of the rising or falling edge of the input L3_ECHO_CLK*n* (see Figure 10). Input timings are measured at the pins.
3. For DDR, the input data will typically follow the edge of L3_ECHO_CLK*n* as shown in Figure 10. For consistency with other input setup time specifications, this will be treated as negative input setup time.
4. t_{L3_CLK}/4 is one-fourth the period of L3_CLK*n*. This parameter indicates that the MPC7457 can latch an input signal that is valid for only a short time before and a short time after the midpoint between the rising and falling (or falling and rising) edges of L3_ECHO_CLK*n* at any frequency.
5. All output specifications are measured from the midpoint voltage of the rising (or for DDR write data, also the falling) edge of L3_CLK to the midpoint of the signal in question. The output timings are measured at the pins. All output timings assume a purely resistive 50-Ω load (see Figure 8).
6. For DDR, the output data will typically lead the edge of L3_CLK*n* as shown in Figure 10. For consistency with other output valid time specifications, this will be treated as negative output valid time.
7. t_{L3_CLK}/4 is one-fourth the period of L3_CLK*n*. This parameter indicates that the specified output signal is actually launched by an internal clock delayed in phase by 90°. Therefore, there is a frequency component to the output valid and output hold times such that the specified output signal will be valid for approximately one L3_CLK period starting three-fourths of a clock before the edge on which the SRAM will sample it and ending one-fourth of a clock period after the edge it will be sampled.
8. Assumes default value of L3OHCR. See Section 5.2.4.1, “Effects of L3OHCR Settings on L3 Bus AC Specifications,” for more information.
9. L3 I/O voltage mode must be configured by L3VSEL as described in Table 3, and voltage supplied at GV_{DD} must match mode selected as specified in Table 4. See Table 22 for revision level information and part marking.

Figure 16 provides the boundary-scan timing diagram.

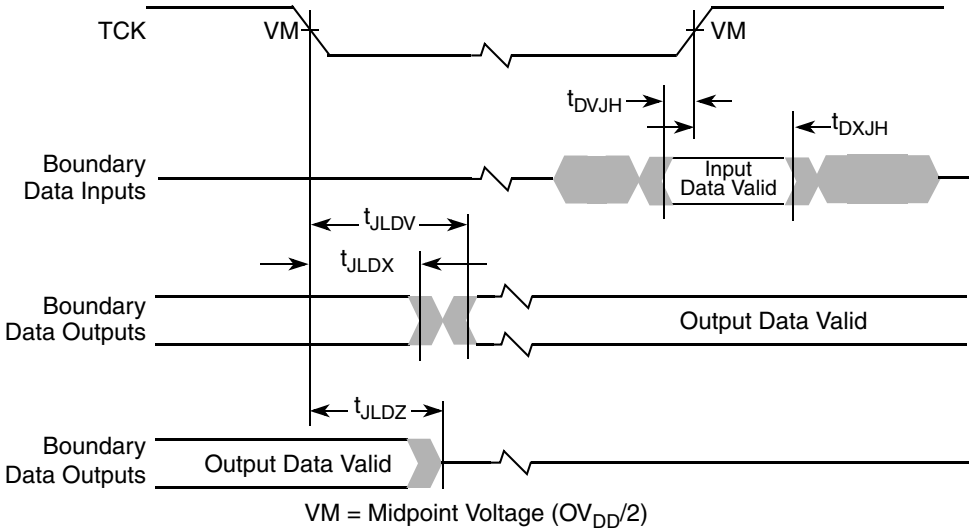


Figure 16. Boundary-Scan Timing Diagram

Figure 17 provides the test access port timing diagram.

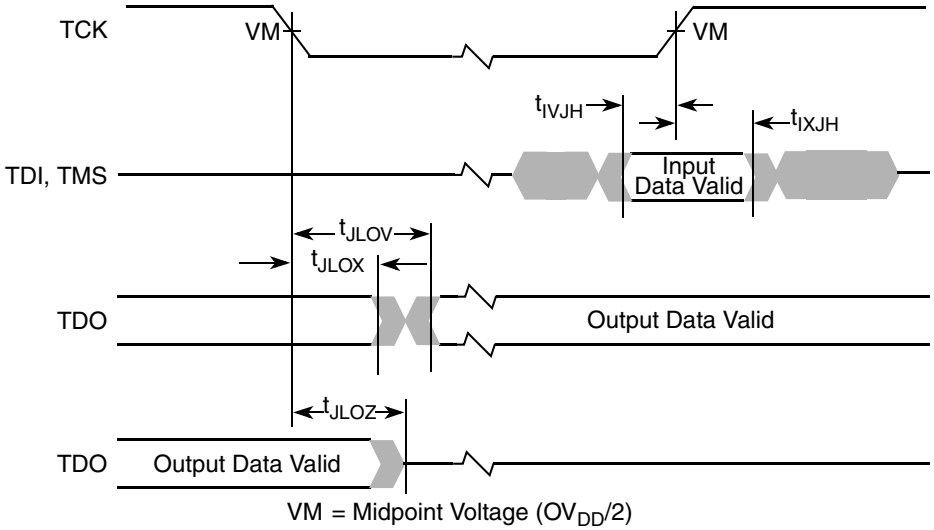
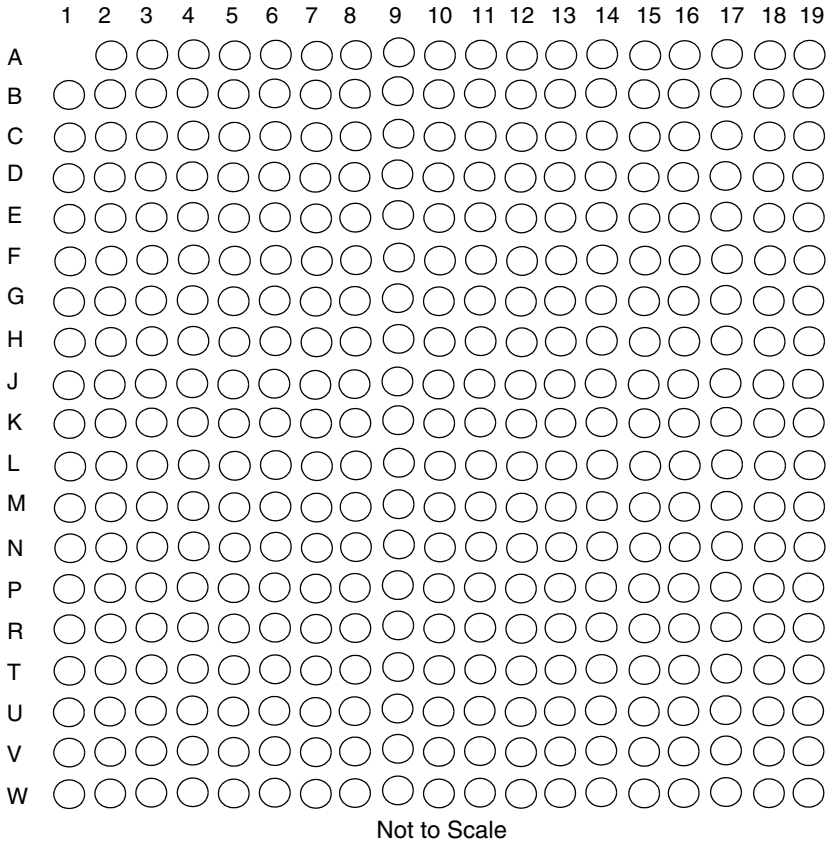


Figure 17. Test Access Port Timing Diagram

6 Pin Assignments

Figure 18 (Part A) shows the pinout of the MPC7447, 360 CBGA package as viewed from the top surface. Part B shows the side profile of the CBGA package to indicate the direction of the top surface view.

Part A



Part B

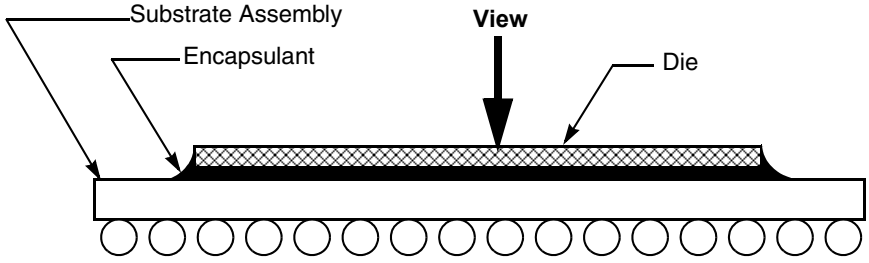


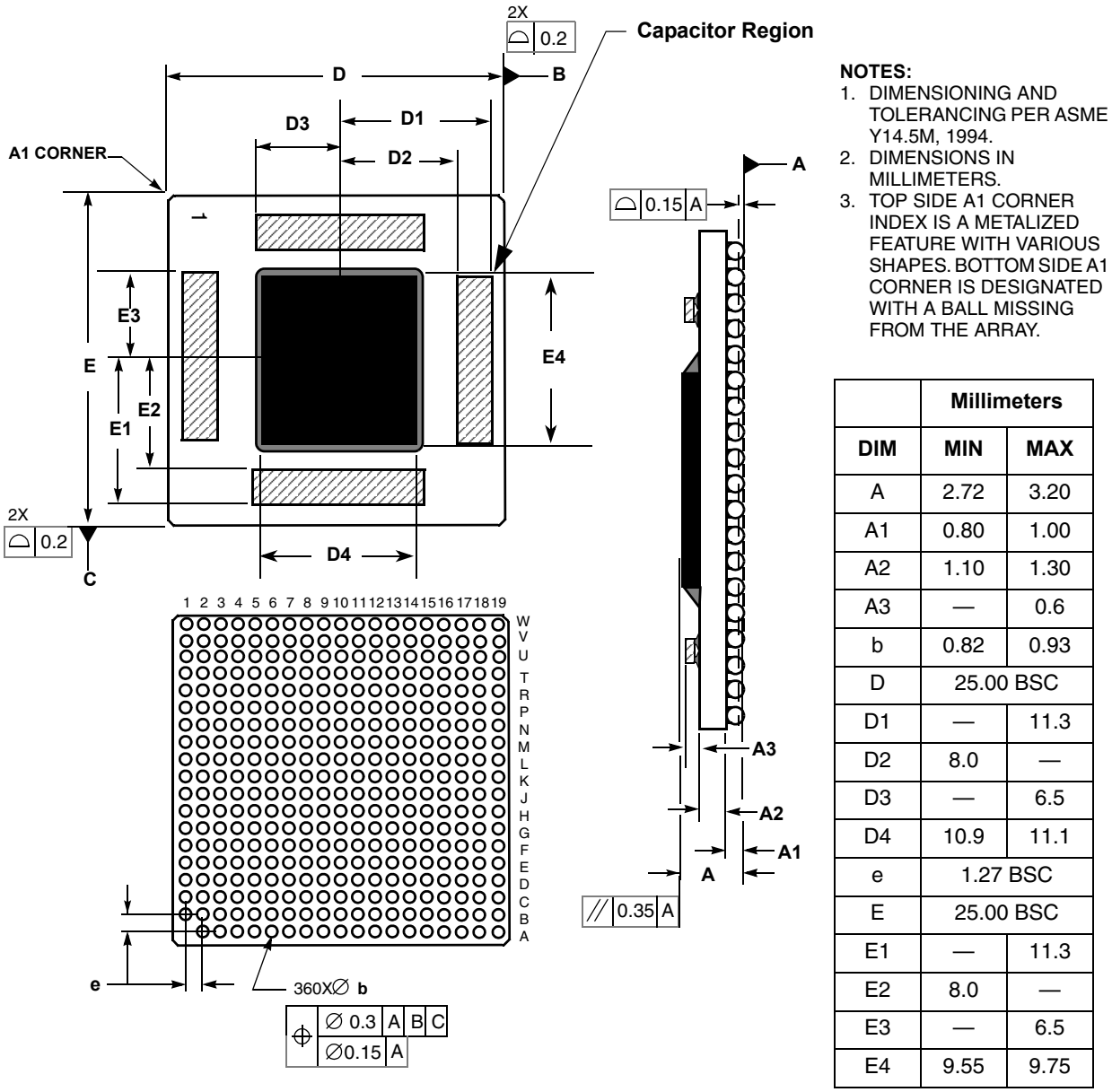
Figure 18. Pinout of the MPC7447, 360 CBGA Package as Viewed from the Top Surface

Table 17. Pinout Listing for the MPC7457, 483 CBGA Package (continued)

Signal Name	Pin Number	Active	I/O	I/F Select [1]	Notes
L1_TSTCLK	H4	High	Input	BVSEL	10
L2_TSTCLK	J2	High	Input	BVSEL	12
L3VSEL	A4	High	Input	N/A	6, 7
L3ADDR[18:0]	H11, F20, J16, E22, H18, G20, F22, G22, H20, K16, J18, H22, J20, J22, K18, K20, L16, K22, L18	High	Output	L3VSEL	
L3_CLK[0:1]	V22, C17	High	Output	L3VSEL	
$\overline{\text{L3\_CNTL}}$[0:1]	L20, L22	Low	Output	L3VSEL	
L3DATA[0:63]	AA19, AB20, U16, W18, AA20, AB21, AA21, T16, W20, U18, Y22, R16, V20, W22, T18, U20, N18, N20, N16, N22, M16, M18, M20, M22, R18, T20, U22, T22, R20, P18, R22, M15, G18, D22, E20, H16, C22, F18, D20, B22, G16, A21, G15, E17, A20, C19, C18, A19, A18, G14, E15, C16, A17, A16, C15, G13, C14, A14, E13, C13, G12, A13, E12, C12	High	I/O	L3VSEL	
L3DP[0:7]	AB19, AA22, P22, P16, C20, E16, A15, A12	High	I/O	L3VSEL	
L3_ECHO_CLK[0,2]	V18, E18	High	Input	L3VSEL	
L3_ECHO_CLK[1,3]	P20, E14	HIgh	I/O	L3VSEL	
$\overline{\text{LSSD\_MODE}}$	F6	Low	Input	BVSEL	7, 13
$\overline{\text{MCP}}$	B8	Low	Input	BVSEL	
No Connect	A8, A11, B6, B11, C11, D11, D3, D5, E11, E7, F2, F11, G2, H9	—	—	N/A	14
OV_{DD}	B3, C5, C7, C10, D2, E3, E9, F5, G3, G9, H7, J5, K3, L7, M5, N3, P7, R4, T3, U5, U7, U11, U15, V3, V9, V13, Y2, Y5, Y7, Y10, Y17, Y19, AA4, AA15	—	—	N/A	
PLL_CFG[0:4]	A2, F7, C2, D4, H8	High	Input	BVSEL	
$\overline{\text{PMON\_IN}}$	E6	Low	Input	BVSEL	15
$\overline{\text{PMON\_OUT}}$	B4	Low	Output	BVSEL	
$\overline{\text{QACK}}$	K7	Low	Input	BVSEL	
$\overline{\text{QREQ}}$	Y1	Low	Output	BVSEL	
$\overline{\text{SHD}}$[0:1]	L4, L8	Low	I/O	BVSEL	3
$\overline{\text{SMI}}$	G8	Low	Input	BVSEL	
$\overline{\text{SRESET}}$	G1	Low	Input	BVSEL	
SYSCLK	D6	—	Input	BVSEL	
$\overline{\text{TA}}$	N8	Low	Input	BVSEL	
TBEN	L3	High	Input	BVSEL	
$\overline{\text{TBST}}$	B7	Low	Output	BVSEL	
TCK	J7	High	Input	BVSEL	

8.2 Mechanical Dimensions for the MPC7447, 360 CBGA

Figure 20 provides the mechanical dimensions and bottom surface nomenclature for the MPC7447, 360 CBGA package.



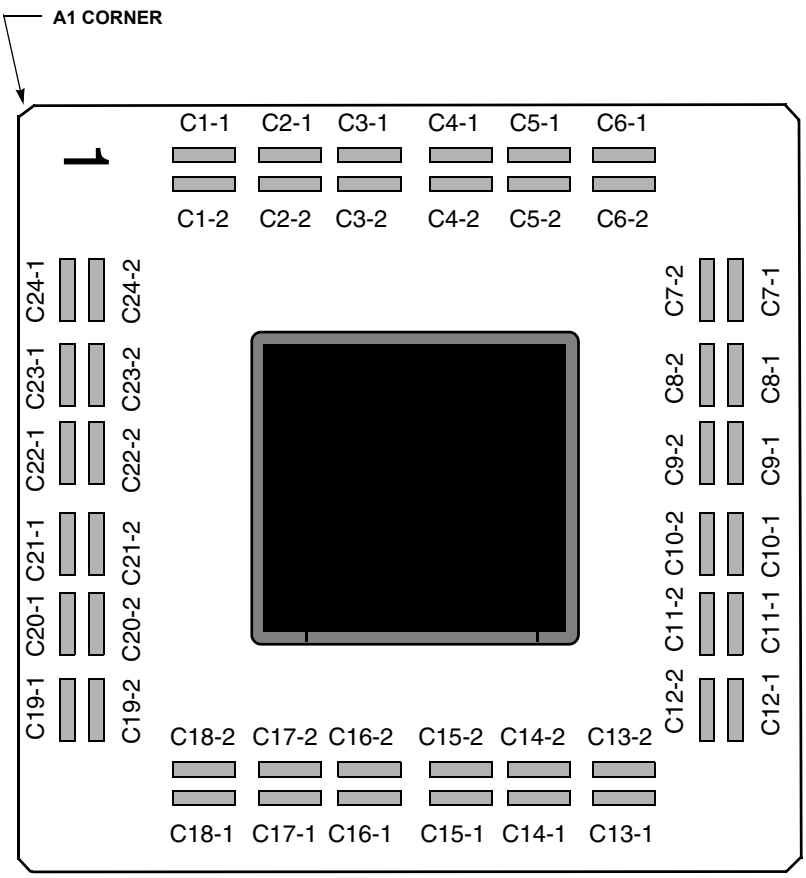
NOTES:
1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
2. DIMENSIONS IN MILLIMETERS.
3. TOP SIDE A1 CORNER INDEX IS A METALIZED FEATURE WITH VARIOUS SHAPES. BOTTOM SIDE A1 CORNER IS DESIGNATED WITH A BALL MISSING FROM THE ARRAY.

	Millimeters	
DIM	MIN	MAX
A	2.72	3.20
A1	0.80	1.00
A2	1.10	1.30
A3	—	0.6
b	0.82	0.93
D	25.00 BSC	
D1	—	11.3
D2	8.0	—
D3	—	6.5
D4	10.9	11.1
e	1.27 BSC	
E	25.00 BSC	
E1	—	11.3
E2	8.0	—
E3	—	6.5
E4	9.55	9.75

Figure 20. Mechanical Dimensions and Bottom Surface Nomenclature for the MPC7447, 360 CBGA Package

8.6 Substrate Capacitors for the MPC7457, 483 CBGA or RoHS BGA

Figure 23 shows the connectivity of the substrate capacitor pads for the MPC7457, 483 CBGA or RoHS BGA. All capacitors are 100 nF.



Capacitor	Pad Number	
	-1	-2
C1	GND	OV_{DD}
C2	GND	V_{DD}
C3	GND	GV_{DD}
C4	GND	V_{DD}
C5	GND	V_{DD}
C6	GND	GV_{DD}
C7	GND	V_{DD}
C8	GND	V_{DD}
C9	GND	GV_{DD}
C10	GND	V_{DD}
C11	GND	V_{DD}
C12	GND	GV_{DD}
C13	GND	V_{DD}
C14	GND	V_{DD}
C15	GND	V_{DD}
C16	GND	OV_{DD}
C17	GND	V_{DD}
C18	GND	OV_{DD}
C19	GND	V_{DD}
C20	GND	V_{DD}
C21	GND	OV_{DD}
C22	GND	V_{DD}
C23	GND	V_{DD}
C24	GND	V_{DD}

Figure 23. Substrate Bypass Capacitors for the MPC7457, 483 CBGA or RoHS BGA

Table 18. MPC7457 Microprocessor PLL Configuration Example for 1267 MHz Parts (continued)

PLL_CFG[0:4]	Bus-to-Core Multiplier	Core-to-VCO Multiplier	Example Bus-to-Core Frequency in MHz (VCO Frequency in MHz)							
			Bus (SYSCLK) Frequency							
			33.3 MHz	50 MHz	66.6 MHz	75 MHz	83 MHz	100 MHz	133 MHz	167 MHz
01111	9x	2x			600 (1200)	675 (1350)	747 (1494)	900 (1800)	1197 (2394)	
01110	9.5x	2x			633 (1266)	712 (1524)	789 (1578)	950 (1900)	1264 (2528)	
10101	10x	2x			667 (1333)	750 (1500)	830 (1660)	1000 (2000)		
10001	10.5x	2x			700 (1400)	938 (1876)	872 (1744)	1050 (2100)		
10011	11x	2x			733 (1466)	825 (1650)	913 (1826)	1100 (2200)		
00000	11.5x	2x			766 (532)	863 (1726)	955 (1910)	1150 (2300)		
10111	12x	2x		600 (1200)	800 (1600)	900 (1800)	996 (1992)	1200 (2400)		
11111	12.5x	2x		600 (1200)	833 (1666)	938 (1876)	1038 (2076)	1250 (2500)		
01011	13x	2x		650 (1300)	865 (1730)	975 (1950)	1079 (2158)			
11100	13.5x	2x		675 (1350)	900 (1800)	1013 (2026)	1121 (2242)			
11001	14x	2x		700 (1400)	933 (1866)	1050 (2100)	1162 (2324)			
00011	15x	2x		750 (1500)	1000 (2000)	1125 (2250)	1245 (2490)			
11011	16x	2x		800 (1600)	1066 (2132)	1200 (2400)				
00001	17x	2x		850 (1900)	1132 (2264)					
00101	18x	2x	600 (1200)	900 (1800)	1200 (2400)					
00111	20x	2x	667 (1334)	1000 (2000)						
01001	21x	2x	700 (1400)	1050 (2100)						
01101	24x	2x	800 (1600)	1200 (2400)						
11101	28x	2x	933 (1866)							
00110	PLL bypass		PLL off, SYSCLK clocks core circuitry directly							

If address or data parity is not used by the system, and the respective parity checking is disabled through HID0, the input receivers for those pins are disabled, and those pins do not require pull-up resistors and should be left unconnected by the system. If all parity generation is disabled through HID0, all parity checking should also be disabled through HID0, and all parity pins may be left unconnected by the system.

The L3 interface does not normally require pull-up resistors. Unused L3_ADDR signals are driven low when the SRAM is configured to be less than 1 M in size via L3CR. For example, L3_ADD[18] will be driven low if the SRAM size is configured to be 2 M; likewise, L3_ADDR[18:17] will be driven low if the SRAM size is configured to be 1 M.

9.7 JTAG Configuration Signals

Boundary-scan testing is enabled through the JTAG interface signals. The $\overline{\text{TRST}}$ signal is optional in the IEEE 1149.1 specification, but is provided on all processors that implement the PowerPC architecture. While it is possible to force the TAP controller to the reset state using only the TCK and TMS signals, more reliable power-on reset performance will be obtained if the $\overline{\text{TRST}}$ signal is asserted during power-on reset. Because the JTAG interface is also used for accessing the common on-chip processor (COP) function, simply tying $\overline{\text{TRST}}$ to $\overline{\text{HRESET}}$ is not practical.

The COP function of these processors allows a remote computer system (typically, a PC with dedicated hardware and debugging software) to access and control the internal operations of the processor. The COP interface connects primarily through the JTAG port of the processor, with some additional status monitoring signals. The COP port requires the ability to independently assert $\overline{\text{HRESET}}$ or $\overline{\text{TRST}}$ in order to fully control the processor. If the target system has independent reset sources, such as voltage monitors, watchdog timers, power supply failures, or push-button switches, the COP reset signals must be merged into these signals with logic.

The arrangement shown in Figure 26 allows the COP port to independently assert $\overline{\text{HRESET}}$ or $\overline{\text{TRST}}$, while ensuring that the target can drive $\overline{\text{HRESET}}$ as well. If the JTAG interface and COP header will not be used, $\overline{\text{TRST}}$ should be tied to $\overline{\text{HRESET}}$ through a 0-Ω isolation resistor so that it is asserted when the system reset signal ($\overline{\text{HRESET}}$) is asserted, ensuring that the JTAG scan chain is initialized during power-on. While Freescale recommends that the COP header be designed into the system as shown in Figure 26, if this is not possible, the isolation resistor will allow future access to $\overline{\text{TRST}}$ in the case where a JTAG interface may need to be wired onto the system in debug situations.

The COP header shown in Figure 26 adds many benefits—breakpoints, watchpoints, register and memory examination/modification, and other standard debugger features are possible through this interface—and can be as inexpensive as an unpopulated footprint for a header to be added when needed.

The COP interface has a standard header for connection to the target system, based on the 0.025" square-post, 0.100" centered header assembly (often called a Berg header). The connector typically has pin 14 removed as a connector key.

There is no standardized way to number the COP header shown in Figure 26; consequently, many different pin numbers have been observed from emulator vendors. Some are numbered top-to-bottom then left-to-right, while others use left-to-right then top-to-bottom, while still others number the pins counter clockwise from pin 1 (as with an IC). Regardless of the numbering, the signal placement recommended in Figure 26 is common to all known emulators.

The $\overline{\text{QACK}}$ signal shown in Figure 26 is usually connected to the PCI bridge chip in a system and is an input to the MPC7457 informing it that it can go into the quiescent state. Under normal operation this occurs during a low-power mode selection. In order for COP to work, the MPC7457 must see this signal asserted (pulled down). While shown on the COP header, not all emulator products drive this signal. If the product does not, a pull-down resistor can be populated to assert this signal. Additionally, some emulator products implement open-drain type outputs and can only drive $\overline{\text{QACK}}$ asserted; for these tools, a pull-up resistor can be implemented to ensure this signal is deasserted when it is not being driven by the tool. Note that the pull-up and pull-down resistors on the $\overline{\text{QACK}}$ signal are mutually exclusive and it is never necessary to populate both in a system. To preserve correct power-down operation, $\overline{\text{QACK}}$ should be merged via logic so that it also can be driven by the PCI bridge.

9.8 Thermal Management Information

This section provides thermal management information for the ceramic ball grid array (CBGA) package for air-cooled applications. Proper thermal control design is primarily dependent on the system-level design—the heat sink, airflow, and thermal interface material. To reduce the die-junction temperature, heat sinks may be attached to the package by several methods—spring clip to holes in the printed-circuit board or package, and mounting clip and screw assembly (see Figure 27); however, due to the potential large mass of the heat sink, attachment through the printed-circuit board is suggested. If a spring clip is used, the spring force should not exceed 10 pounds.

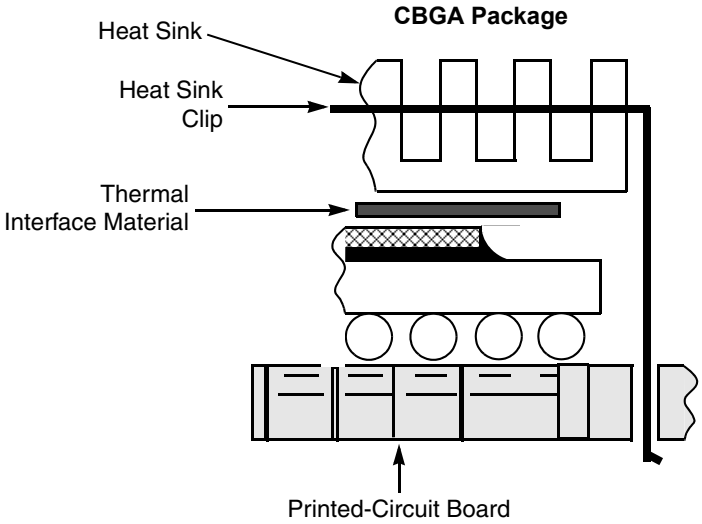


Figure 27. Package Exploded Cross-Sectional View with Several Heat Sink Options

The board designer can choose between several types of heat sinks to place on the MPC7457. There are several commercially available heat sinks for the MPC7457 provided by the following vendors:

Aavid Thermalloy 80 Commercial St. Concord, NH 03301 Internet: www.aavidthermalloy.com	603-224-9988
Alpha Novatech 473 Sapena Ct. #15 Santa Clara, CA 95054 Internet: www.alphanovatech.com	408-749-7601
Calgreg Thermal Solutions 60 Alhambra Road Warwick, RI 02886 Internet: www.calgregthermalsolutions.com	401-732-8100
International Electronic Research Corporation (IERC) 413 North Moss St. Burbank, CA 91502 Internet: www.ctscorp.com	818-842-7277

Tyco Electronics Chip Coolers™ P.O. Box 3668 Harrisburg, PA 17105-3668 Internet: www.chipcoolers.com	800-522-6752
Wakefield Engineering 33 Bridge St. Pelham, NH 03076 Internet: www.wakefield.com	603-635-5102

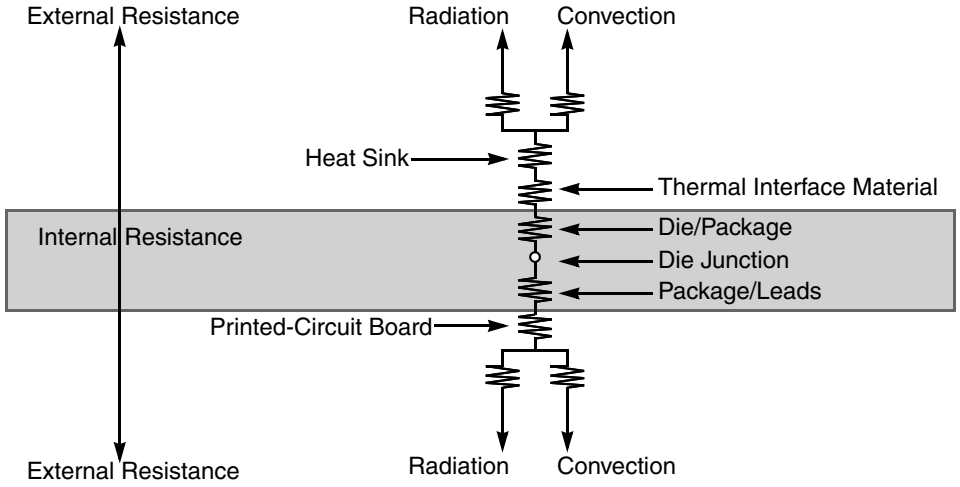
Ultimately, the final selection of an appropriate heat sink depends on many factors, such as thermal performance at a given air velocity, spatial volume, mass, attachment method, assembly, and cost.

9.8.1 Internal Package Conduction Resistance

For the exposed-die packaging technology, shown in Table 5, the intrinsic conduction thermal resistance paths are as follows:

- The die junction-to-case (actually top-of-die since silicon die is exposed) thermal resistance
- The die junction-to-ball thermal resistance

Figure 28 depicts the primary heat transfer path for a package with an attached heat sink mounted to a printed-circuit board.



(Note the internal versus external package resistance.)

Figure 28. C4 Package with Heat Sink Mounted to a Printed-Circuit Board

Heat generated on the active side of the chip is conducted through the silicon, through the heat sink attach material (or thermal interface material), and finally to the heat sink where it is removed by forced-air convection.

Because the silicon thermal resistance is quite small, for a first-order analysis, the temperature drop in the silicon may be neglected. Thus, the thermal interface material and the heat sink conduction/convective thermal resistances are the dominant terms.

9.8.2 Thermal Interface Materials

A thermal interface material is recommended at the package lid-to-heat sink interface to minimize the thermal contact resistance. For those applications where the heat sink is attached by spring clip mechanism, Figure 29 shows the thermal performance of three thin-sheet thermal-interface materials (silicone, graphite/oil, floroether oil), a bare joint, and a joint with thermal grease as a function of contact pressure. As shown, the performance of these thermal interface materials improves with increasing contact pressure. The use of thermal grease significantly reduces the interface thermal resistance. That is, the bare joint results in a thermal resistance approximately seven times greater than the thermal grease joint.

Often, heat sinks are attached to the package by means of a spring clip to holes in the printed-circuit board (see Figure 27). Therefore, the synthetic grease offers the best thermal performance, considering the low interface pressure and is recommended due to the high power dissipation of the MPC7457. Of course, the selection of any thermal interface material depends on many factors—thermal performance requirements, manufacturability, service temperature, dielectric properties, cost, etc.

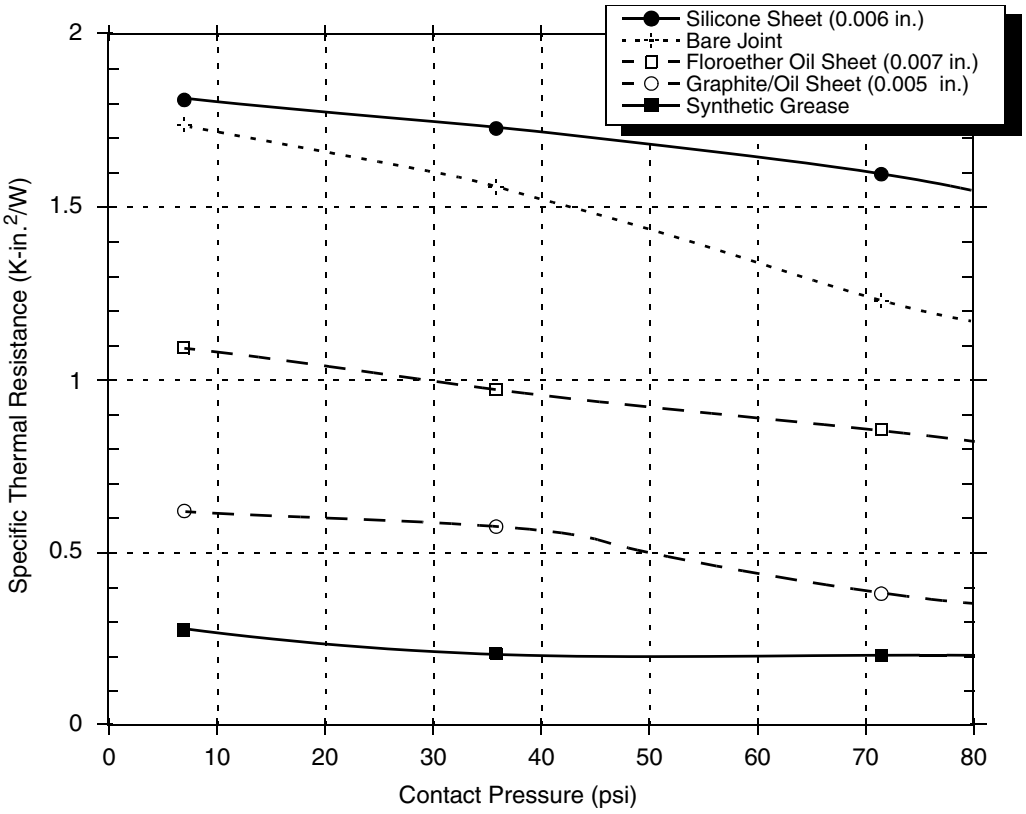


Figure 29. Thermal Performance of Select Thermal Interface Material

The board designer can choose between several types of thermal interface. Heat sink adhesive materials should be selected based on high conductivity, yet adequate mechanical strength to meet equipment shock/vibration requirements. There are several commercially available thermal interfaces and adhesive materials provided by the following vendors:

example, assuming a T_a of 30°C, a T_r of 5°C, a CBGA package $R_{\theta JC}$ = 0.1, and a typical power consumption (P_d) of 18.7 W, the following expression for T_j is obtained:

Die-junction temperature: $T_j = 30°C + 5°C + (0.1°C/W + 1.5°C/W + \theta_{sa}) \times 18.7\ W$

For this example, a $R_{\theta sa}$ value of 2.1°C/W or less is required to maintain the die junction temperature below the maximum value of Table 4.

Though the die junction-to-ambient and the heat sink-to-ambient thermal resistances are a common figure-of-merit used for comparing the thermal performance of various microelectronic packaging technologies, one should exercise caution when only using this metric in determining thermal management because no single parameter can adequately describe three-dimensional heat flow. The final die-junction operating temperature is not only a function of the component-level thermal resistance, but the system-level design and its operating conditions. In addition to the component's power consumption, a number of factors affect the final operating die-junction temperature—airflow, board population (local heat flux of adjacent components), heat sink efficiency, heat sink attach, heat sink placement, next-level interconnect technology, system air temperature rise, altitude, etc.

Due to the complexity and the many variations of system-level boundary conditions for today's microelectronic equipment, the combined effects of the heat transfer mechanisms (radiation, convection, and conduction) may vary widely. For these reasons, we recommend using conjugate heat transfer models for the board, as well as system-level designs.

For system thermal modeling, the MPC7447 and MPC7457 thermal model is shown in Figure 30. Four volumes will be used to represent this device. Two of the volumes, solder ball, and air and substrate, are modeled using the package outline size of the package. The other two, die, and bump and underfill, have the same size as the die. The silicon die should be modeled 9.64 × 11.0 × 0.74 mm with the heat source applied as a uniform source at the bottom of the volume. The bump and underfill layer is modeled as 9.64 × 11.0 × 0.069 mm (or as a collapsed volume) with orthotropic material properties: 0.6 W/(m • K) in the xy-plane and 2 W/(m • K) in the direction of the z-axis. The substrate volume is 25 × 25 × 1.2 mm (MPC7447) or 29 × 29 × 1.2 mm (MPC7457), and this volume has 18 W/(m • K) isotropic conductivity. The solder ball and air layer is modeled with the same horizontal dimensions as the substrate and is 0.9 mm thick. It can also be modeled as a collapsed volume using orthotropic material properties: 0.034 W/(m • K) in the xy-plane direction and 3.8 W/(m • K) in the direction of the z-axis.

Table 24. Part Numbers Addressed by MPC7457TRX*nnnn*LB Series Hardware Specifications Addendum (Document Order No. MPC7457ECS02AD)

MC	7457	T	RX	*nnnn*	L	*x*

Product Code	Part Identifier	Specification Modifier	Package	Processor Frequency	Application Modifier	Revision Level
MC	7457	T = Extended Temperature Device	RX = CBGA	1000 1267	L: 1.3 V ± 50 mV –40° to 105°C	C: 1.2; PVR = 8002 0102

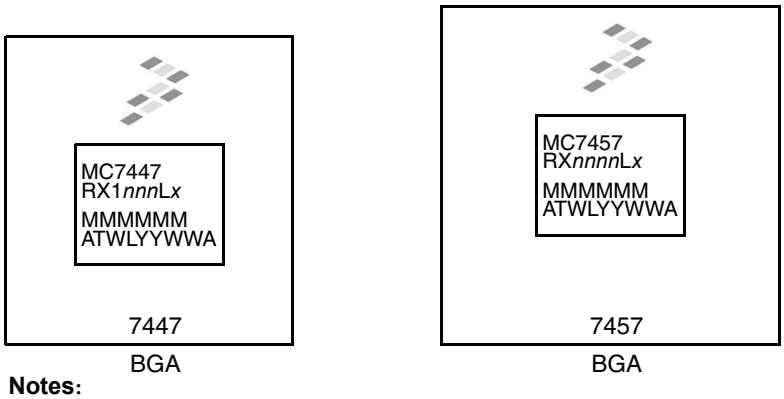
Table 25. Part Numbers Addressed by MPC7457TRX*nnnn*N*x* Series Hardware Specifications Addendum (Document Order No. MPC7457ECS03AD)

MC	74*x*7	T	RX	*nnnn*	N	*x*

Product Code	Part Identifier	Specification Modifier	Package	Processor Frequency	Application Modifier	Revision Level
MC	7447	T = Extended Temperature Device	RX = CBGA	733 1000	N: 1.1 V ± 50 mV –40° to 105°C	B: 1.1; PVR = 8002 0101
	7457					C: 1.2; PVR = 8002 0102

10.3 Part Marking

Parts are marked as the examples shown in Figure 31.



Notes:
MMMMMM is the 6-digit mask number.
ATWLYYWWA is the traceability code.

Figure 31. Part Marking for BGA Device

11 Document Revision History

Table 26 provides a revision history for this hardware specification.

Table 26. Document Revision History

Revision Number	Date	Substantive Change(s)
8	04/09/2013	Updated template. Updated Table 14 “L3 Bus Interface AC Timing Specifications for PB2 and Late Write SRAMs”. Moved Revision History to the end of the document.
7	3/28/2006	Updated template. Section 2, reworded L1 and L2 cache descriptions. Removed note references for $\overline{CI}$ and $\overline{WT}$ in Table 12. Added VG package signifier for 7457 only.
6	7/22/2005	Revised Note in Section 9.2.
		Added heat sink vendor to list in Section 9.8.
		Corrected bump and underfill model dimension in Section 9.8.3.
5	9/9/2004	Updated document to new Freescale template.
		Updated section numbering and changed reference from part number specifications to addendums.
		Added Rev. 1.2 devices, including increased L3 clock max frequency to 250 MHz and improved L3 AC timing.
		Table 5: Added CTE information.
		Table 8: Modified jitter specifications to conform to JEDEC standards, changed jitter specification to cycle-to-cycle jitter (instead of long- and short-term jitter); changed jitter bandwidth recommendations.
		Table 13: Deleted note 9 and renumbered.
		Table 14: Deleted note 5 and renumbered.
		Table 17: Revised note 6.
		Added Section 9.1.3.
		Section 9.2: Changed filter resistor recommendations. Recommend 10 Ω resistor for all production devices, including production Rev. 1.1 devices. 400 Ω resistor needed only for early Rev. 1.1 devices.
		Table 22: Reversed the order of revision numbers.
		Added Tables 25 and 26.
4.1		Section 9.1.1: Corrected note regarding different PLL configurations for earlier devices; all MPC7457 devices to date conform to this table.
		Section 9.6: Added information about unused L3_ADDR signals.
		Table 24: Changed title to include document order information for MPC74x7RXnnnnNx series part number specification.